

Notice of References Cited

Application/Control No.

09/595,783

Applicant(s)/Patent Under
Reexamination
ADAMS ET AL.

Examiner

Hunter B. Lonsberry

Art Unit

2611

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,173,317	01-2001	Chaddha et al.	709/219
	B	US-5,512,935	04-1996	Majeti et al.	725/33
	C	US-5,991,799	11-1999	Yen et al.	709/218
	D	US-6,128,653 A	10-2000	del Val et al.	709/219
	E	US-			
	F	US-			
	G	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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